



Maximum Ratings

Parameter	Symbol	Value	Unit
Drain Source voltage slope	dv/dt	50	V/ns
$V_{\rm DS}$ = 400 V, $I_{\rm D}$ = 11.6 A, $T_{\rm j}$ = 125 °C			

Thermal Characteristics

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
Thermal resistance, junction - case	R_{thJC}	-	-	1	K/W
Thermal resistance, junction - ambient, leaded	R_{thJA}	-	-	62	
SMD version, device on PCB:	R _{thJA}				
@ min. footprint		-	-	62	
@ 6 cm ² cooling area ²⁾		-	35	-	
Soldering temperature, wavesoldering	T_{sold}	-	-	260	°C
1.6 mm (0.063 in.) from case for 10s					

Electrical Characteristics, at *T*j=25°C unless otherwise specified

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Drain-source breakdown voltage	V _{(BR)DSS}	V _{GS} =0V, I _D =0.25mA	500	-	-	V
Drain-Source avalanche	V _{(BR)DS}	V _{GS} =0V, I _D =11.6A	-	600	-	
breakdown voltage						
Gate threshold voltage	V _{GS(th)}	$I_{\rm D}$ =500 $\mu{\rm A}, V_{\rm GS}$ = $V_{\rm DS}$	2.1	3	3.9	
Zero gate voltage drain current	I _{DSS}	V _{DS} =500V, V _{GS} =0V,				μΑ
		<i>T</i> _j =25°C,	-	0.1	1	
		<i>T</i> _j =150°C	-	-	100	
Gate-source leakage current	I_{GSS}	V _{GS} =20V, V _{DS} =0V	-	-	100	nA
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =10V, I _D =7A,				Ω
	, ,	<i>T</i> _j =25°C	-	0.34	0.38	
		<i>T</i> _j =150°C		0.92		
Gate input resistance	R _G	f=1MHz, open Drain	-	1.4	-	



Electrical Characteristics, at T_i = 25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Transconductance	<i>9</i> fs	$V_{DS} \ge 2*I_{D}*R_{DS(on)max}$	-	8	-	S
		I _D =7A				
Input capacitance	C _{iss}	V _{GS} =0V, V _{DS} =25V,	-	1200	-	pF
Output capacitance	Coss	f=1MHz	-	400	-	
Reverse transfer capacitance	C _{rss}		-	30	-	
Effective output capacitance,3)	C _{o(er)}	V _{GS} =0V,	-	45	-	pF
energy related	, ,	V _{DS} =0V to 400V				
Effective output capacitance,4)	C _{o(tr)}		-	92	-	
time related	, ,					
Turn-on delay time	t _{d(on)}	V _{DD} =380V, V _{GS} =0/10V,	-	10	-	ns
Rise time	$t_{\rm r}$	I _D =11.6A, R _G =6.8Ω	-	8	-	
Turn-off delay time	t _{d(off)}		-	45	-	
Fall time	<i>t</i> _f		-	8	-	

Gate Charge Characteristics

Gate to source charge	Q_{gs}	V _{DD} =400V, I _D =11.6A	-	5	-	nC
Gate to drain charge	Q _{gd}		-	26	-	
Gate charge total	Qg	V _{DD} =400V, I _D =11.6A,	-	49	-	
		V _{GS} =0 to 10V				
Gate plateau voltage	V _(plateau)	V _{DD} =400V, I _D =11.6A	-	5	1	V

⁰J-STD20 and JESD22

¹Repetitve avalanche causes additional power losses that can be calculated as $P_{AV} = E_{AR} * f$.

²Device on 40mm*40mm*1.5mm epoxy PCB FR4 with 6cm² (one layer, 70 μm thick) copper area for drain connection. PCB is vertical without blown air.

 $^{^3}C_{\mathrm{o(er)}}$ is a fixed capacitance that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .

 $^{^4}C_{
m o(tr)}$ is a fixed capacitance that gives the same charging time as $C_{
m oss}$ while $V_{
m DS}$ is rising from 0 to 80% $V_{
m DSS}$.

 $^{^{5}}$ I_{SD}<=I_D, di/dt<=400A/us, V_{DClink}=400V, V_{peak}<V_{BR, DSS}, T_j<T_{j,max}. Identical low-side and high-side switch.



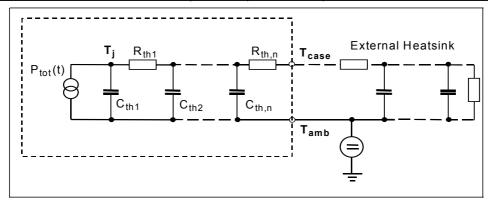


Electrical Characteristics, at T_j = 25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	1
Inverse diode continuous	IS	T _C =25°C	-	-	11.6	Α
forward current						
Inverse diode direct current,	/ _{SM}		-	-	34.8	
pulsed						
Inverse diode forward voltage	V_{SD}	V _{GS} =0V, I _F =I _S	-	1	1.2	V
Reverse recovery time	<i>t</i> _{rr}	V _R =400V, I _F =I _S ,	-	380	-	ns
Reverse recovery charge	Q _{rr}	d <i>i</i> _F /d <i>t</i> =100A/μs	-	5.5	-	μC
Peak reverse recovery current	/ _{rrm}		-	38	-	Α
Peak rate of fall of reverse	di _{rr} /dt		-	1100	-	A/µs
recovery current						

Typical Transient Thermal Characteristics

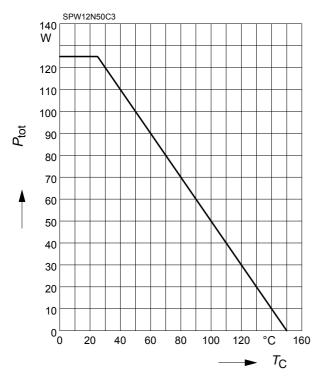
Symbol	Value	Unit	Symbol	Value	Unit
	typ.			typ.	
Thermal r	esistance		Thermal capacitance		
R _{th1}	0.015	K/W	C _{th1}	0.0001878	Ws/K
R _{th2}	0.03		C _{th2}	0.0007106	
R _{th3}	0.056		C _{th3}	0.000988	
R _{th4}	0.197		C _{th4}	0.002791	
R_{th5}	0.216		C _{th5}	0.007285	
R _{th6}	0.083		C _{th6}	0.063	





1 Power dissipation

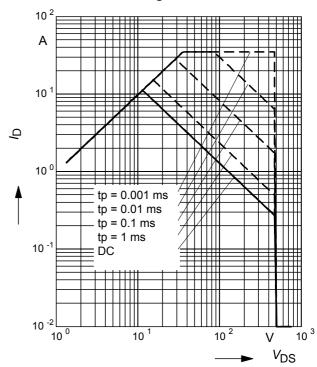
$$P_{\text{tot}} = f(T_{\text{C}})$$



2 Safe operating area

$$I_{D} = f(V_{DS})$$

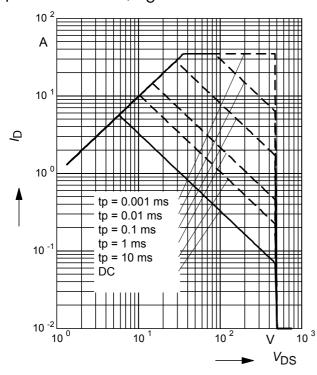
parameter : D = 0 , $T_C = 25$ °C



3 Safe operating area FullPAK

$$I_{\mathsf{D}} = f(V_{\mathsf{DS}})$$

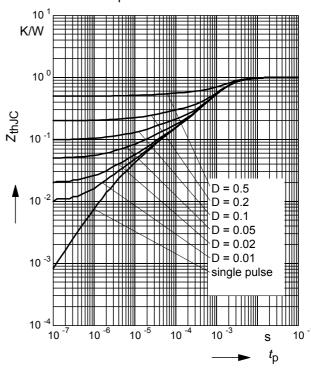
parameter:
$$D = 0$$
, $T_C = 25$ °C



4 Transient thermal impedance

$$Z_{\mathsf{thJC}} = f(t_{\mathsf{p}})$$

parameter: $D = t_p/T$

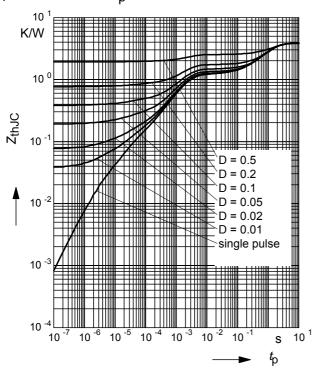




5 Transient thermal impedance FullPAK

$$Z_{\text{thJC}} = f(t_{\text{p}})$$

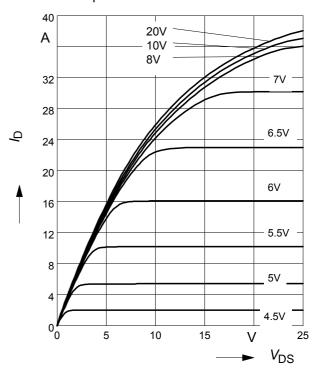
parameter: $D = t_D/t$



6 Typ. output characteristic

 $I_{D} = f(V_{DS}); T_{i}=25^{\circ}C$

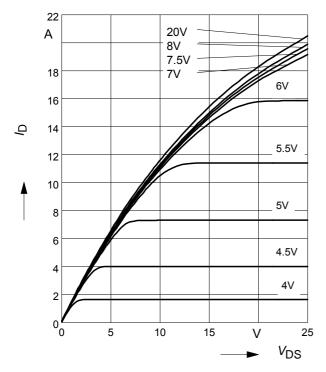
parameter: t_p = 10 μ s, V_{GS}



7 Typ. output characteristic

 $I_{D} = f(V_{DS}); T_{i}=150^{\circ}C$

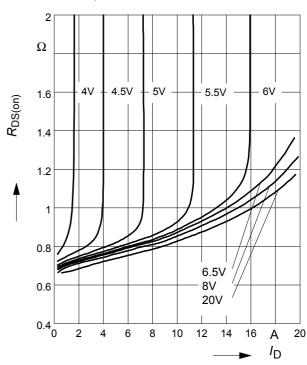
parameter: t_p = 10 μ s, V_{GS}



8 Typ. drain-source on resistance

 $R_{DS(on)} = f(I_D)$

parameter: T_j =150°C, V_{GS}



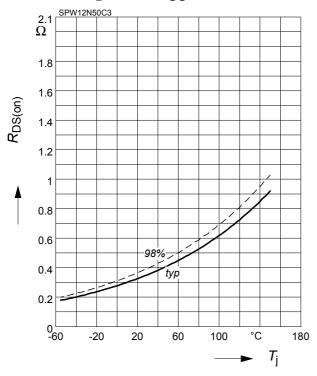
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9 Drain-source on-state resistance

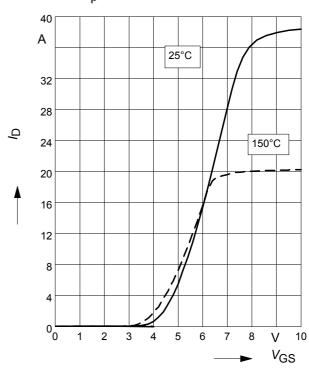
 $R_{DS(on)} = f(T_i)$

parameter : I_D = 7 A, V_{GS} = 10 V



10 Typ. transfer characteristics

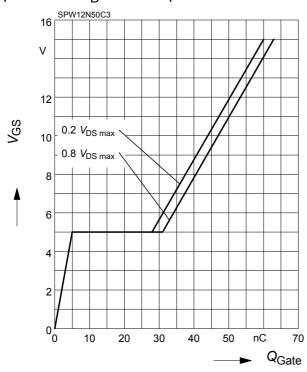
 $I_D = f(V_{GS}); V_{DS} \ge 2 \times I_D \times R_{DS(on)max}$ parameter: $t_D = 10 \mu s$



11 Typ. gate charge

 $V_{GS} = f (Q_{Gate})$

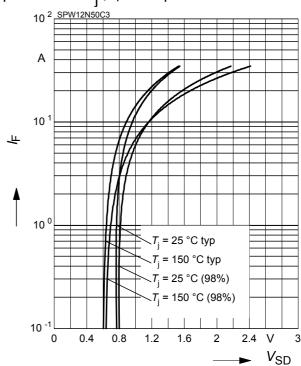
parameter: I_D = 11.6 A pulsed



12 Forward characteristics of body diode

 $I_{\mathsf{F}} = f(\mathsf{V}_{\mathsf{SD}})$

parameter: T_{j} , tp = 10 μ s

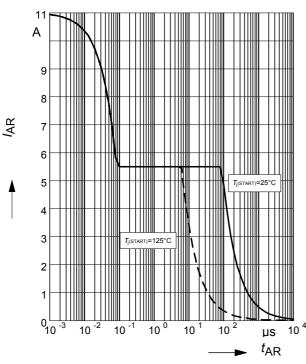




13 Avalanche SOA

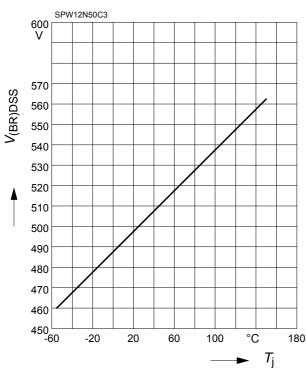
 $I_{AR} = f(t_{AR})$

par.: *T*_i ≤ 150 °C



15 Drain-source breakdown voltage

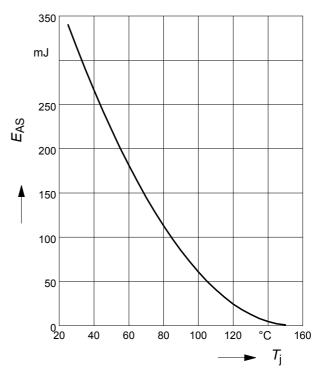
 $V_{(BR)DSS} = f(T_j)$



14 Avalanche energy

 $E_{AS} = f(T_j)$

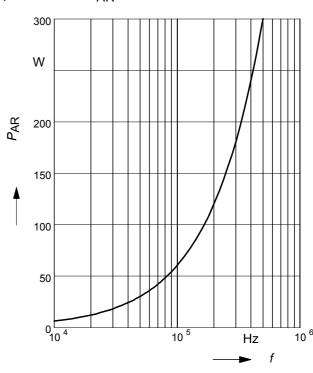
par.: $I_D = 5.5 \text{ A}, V_{DD} = 50 \text{ V}$



16 Avalanche power losses

 $P_{\mathsf{AR}} = f(f)$

parameter: E_{AR}=0.6mJ



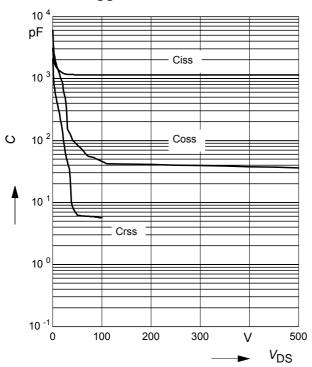
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17 Typ. capacitances

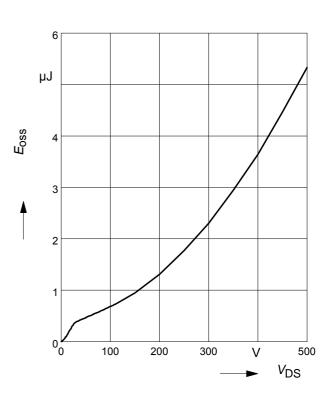
 $C = f(V_{DS})$

parameter: V_{GS}=0V, f=1 MHz

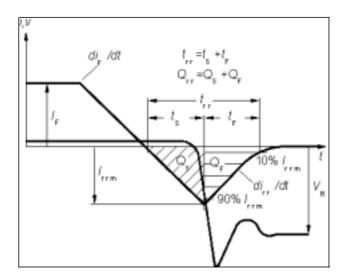


18 Typ. $C_{\rm OSS}$ stored energy

$$E_{\text{oss}} = f(V_{\text{DS}})$$

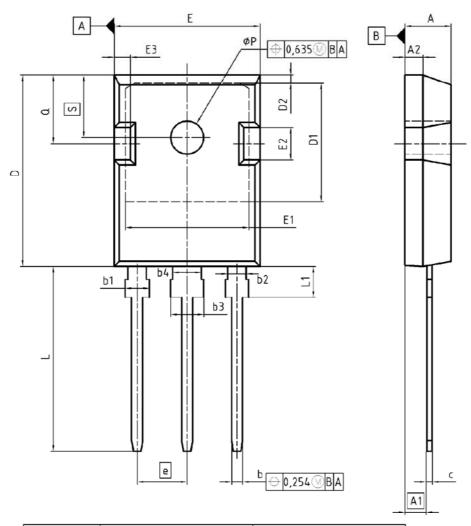


Definition of diodes switching characteristics

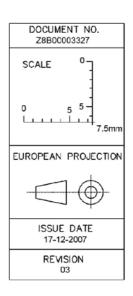




PG-TO-247-3-1



DIM	MILLIM	ETERS	INCH	IES
DIM	MIN	MAX	MIN	MAX
Α	4.90	5.16	0.193	0.203
A1	2.27	2.53	0.089	0.099
A2	1.85	2.11	0.073	0.083
b	1.07	1.33	0.042	0.052
b1	1.90	2.41	0.075	0.095
b2	1.90	2.16	0.075	0.085
b3	2.87	3.38	0.113	0.133
b4	2.87	3.13	0.113	0.123
С	0.55	0.68	0.022	0.027
D	20.82	21.10	0.820	0.831
D1	16.25	17.65	0.640	0.695
D2	1.05	1.35	0.041	0.053
E	15.70	16.03	0.618	0.631
E1	13.10	14.15	0.516	0.557
E2	3.68	5.10	0.145	0.201
E3	1.68	2.60	0.066	0.102
е	5.	44	0.2	14
N	(3	;	3
L	19.80	20.31	0.780	0.799
L1	4.17	4.47	0.164	0.176
øP	3.50	3.70	0.138	0.146
Q	5.49	6.00	0.216	0.236
S	6.04	6.30	0.238 0.3	





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New package outlines TO-247

1 New package outlines TO-247

Assembly capacity extension for CoolMOSTM technology products assembled in lead-free package PG-TO247-3 at subcontractor ASE (Weihai) Inc., China (Changes are marked in blue.)

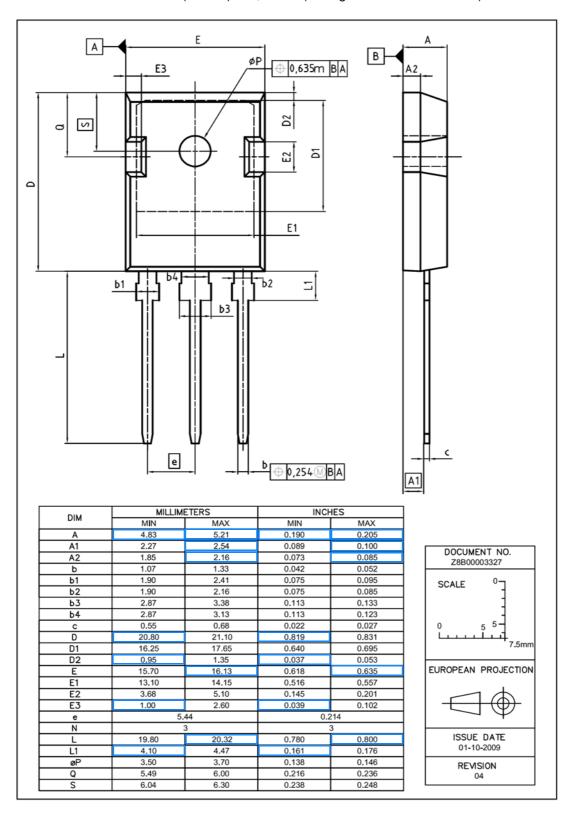


Figure 1 Outlines TO-247, dimensions in mm/inches

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